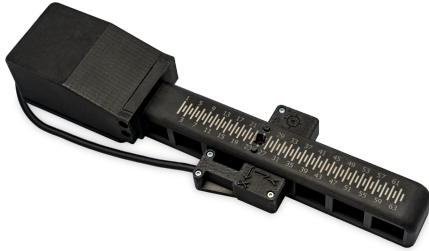




STANDARD TCM ARRAY PROBES

Versatile Eddy Current Array Probes for Efficient Surface Inspection



Large-area testing with position accuracy. The array probes extend the TCM platform with powerful Eddy Current Array (ECA) technology for efficient inspection of surfaces and near-surface areas. By combining multiple sensor elements in compact probe designs, large inspection areas can be covered quickly and efficiently while providing precise positional mapping of inspection data.

The portfolio spans a wide range of probe characteristics – from highly flexible array probes that adapt to complex geometries and very small radii, to semi-flexible designs for demanding inspection geometries, and low-frequency variants optimized for residual wall thickness measurement.

Direction-independent defect detection is available across the range, enabling reliable crack detection regardless of defect orientation.

For applications requiring exceptionally high spatial resolution, a dedicated [High-Resolution Array Probe](#) is available, enabling highly precise detection of the smallest surface defects in critical inspection areas.

When used in combination with the TCM platform, array probes benefit from intuitive app-based operation, automatic probe recognition, and seamless integration into digital inspection workflows.

YOUR ADVANTAGES AT A GLANCE

One array probe portfolio – wide application range:

Flexible, semi-flexible, high-resolution, and low-frequency probes for crack detection and residual wall thickness testing.

Direction-independent defect detection: Reliable results regardless of defect orientation.

The right balance of flexibility and resolution: Optimized probe designs for different geometries, frequencies, and sensitivity requirements.

Efficient large-area inspection: Fast coverage combined with high spatial resolution and precise position assignment.

Seamless TCM integration: Automatic probe recognition, intuitive app-based operation, and full C-scan documentation (PNG / PDF / CSV).

TECHNICAL INFORMATION

FREQUENCY RANGE:	0.1 – 3 MHz 10 – 1000 kHz 0.5 – 30 kHz
PROBE TRACK WIDTH:	2.2 mm 1.4 mm 4.6 mm
ARRAY INSPECTION LENGTH:	140 mm 89 mm 110 mm
NUMBER OF ELEMENTS (STANDARD CONFIGURATION*):	64 64 24

*Customized array probe solutions with up to 512 parallel elements, as well as application-specific shapes and lengths, are available on request.

ACCESSORIES



TCM POSITION ENCODER
Precise Position Tracking for Flexible
Eddy Current Inspections

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